

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,937,049 B2
DATED : August 30, 2005
INVENTOR(S) : Sylvie Wuidart and Claude Zahra

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 3,

Line 45, should read:

-- interval Δt from step 20, an answer request (block 23, SEND --.

Column 6,

Line 32, should read:

-- said second control signal --.

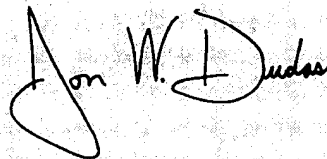
Lines 43-48, should read:

-- 11. A system for testing a set of identical integrated circuit chips in parallel, comprising:

a plural of physical contact pairs intended to contact pads of the respective chips;
and for
transmitting, from a tester a first test control signal to --.

Signed and Sealed this

Eighth Day of November, 2005

A handwritten signature in black ink, appearing to read "Jon W. Dudas", is written over a faint, circular embossed seal of the United States Patent and Trademark Office.

JON W. DUDAS
Director of the United States Patent and Trademark Office